



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT:

Huei Pei Kuo, et. al.

SERIAL NO.:

10/656,635

FILED:

September 4, 2003

FOR:

ANODIZING PROCESS FOR IMPROVING ELECTRONIC EMISSION IN ELECTRONIC

DEVICES

ART UNIT:

2811

EXAMINER:

Hu, Shouxiang.

DOCKET NO.:

10007804-1

CERTIFICATE OF DEPOSIT UNDER 37 C.F.R. § 1.8

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail, postage prepaid, under 37 C.F.R. § 1.8 on the date indicated below and is addressed to Commissioner for Patents, Alexandria, VA 22313-1450.

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DECLARATION OF HUEI PEI KUO UNDER 37 C.F.R. § 1.132

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

I, Huei Pei Kuo declare as follows:

- 1. I am a named inventor in the above-captioned application and the subject matter described and claimed therein.
- 2. It is my understanding that various claims in the above-recited patent application have been rejected in view of United States Patent Application Publication 2003/0143788 A1, filed January 31, 2002, and entitled "Method of Manufacturing an Emitter."
 - 3. The invention as described and claimed in the above-referenced United States

Patent Application Serial Number 10/656,635 was conceived prior to January 31, 2002. I participated in the development of the claimed fabrication methods and electron emission devices and contributed to the disclosures which were subsequently used in preparation of the above-referenced patent application. Exhibit 1 contains a redacted version of the invention disclosures documenting the conception of the invention, which I prepared and had witnessed prior to January 31, 2002.

- 4. Information concerning the invention as described and claimed in the above-referenced Patent Application Serial Number 10/656,635 was communicated by myself and Xia Sheng to the inventors of United States Patent Application Publication 2003/0143788 through our common association as employees of Hewlett Packard Company during a series of in person meetings and teleconferences in the Spring and early Summer of 2001. These communications included a description of the silicon anodization technique and supporting processes, and the design of an electron emitting device and variations thereof produced with the anodization process.
- 5. I declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful, false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code, and that such willful, false statement may jeopardize the validity of the application or any patent issuing thereon.

DATED this 2nd day of November, 2005.

Bucherker

HueiPeiKuo, Inventor of the Invention

Budden

Huei-Pei Kuo, Inventor of the Invention

NOV 1 4 2005

EXHIBIT 1

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	INVENTION DISCLOSURE	/	PAGE ONE OF 4
	PDNO 10007804	DATE RCVD / O/ (SC)	ATTORNEY 746)
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Descriptive Title of Invention:

Merel Mask for Anodization				
Name of Project:				
Product Na	me or Number:			
Was a descr	iption of the invention published	, or are you planning to publish? If so, the	date(s) and publication(s):	
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Was a product including the invention announced, offered for sale, sold, or is such activity proposed? If so, the date(s) and location(s):				
Was the invention disclosed to anyone outside of HP, or will such disclosure occur? If so, the date(s) and name(s):				
	If any of the above situations will	accus within 2 months, not usus ID allows and the L		
Was the inve	ntion described in a lab book or	occur within 3 months, call your IP attorney or the Loother record? If so, please identify (lab boo	egal Department now at 1-898-4919 or 970. ok #, etc.)	898-4919.
Was the inver	ntion built or tested? If so, the d	ate:		
Was this inve	ntion made under a government	contract? If so, the agency and contract r	number:	
Description of Invention: Please preserve all records of the invention and attach additional pages for the following. Each additional page should be signed and dated by the inventor(s) and witness(es).				
 A. Prior solutions and their disadvantages (if available, attach copies of product literature, technical articles, patents, etc.). B. Problems solved by the invention. 				
C. Advantages of the invention over what has been done before.				
 D. Description of the construction and operation of the invention (include appropriate schematic, block, & timing diagrams; drawings; samples; graphs; flowcharts; computer listings; test results; etc.) 				
Signature of Inventor(s): Pursuant to my (our) employment agreement, I (we) submit this disclosure on this date: [].				
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1561 Employee No.	Huei Pei Kuu Name	Huer Berkin	8575407 211-13	? HPL
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530440	Kia Sheng			HPLJ
Employee No.	Name	Signature	Telnet Mailstop	Entity & Lab Name
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PACKARD INVENTION DISCLOSURE		MADANY CONFIDENTIAL	2 2
Signature of Witness(es): (Please try to obtain the signature of		MPANY CONFIDENTIAL	PAGE _2_ OF _4_
The invention was first explained to, and understood	hv me (us) on t	Invention was tirst disclosed.)	1
Full Name Sign	ature		Date of Signature
STEVEN LOUIS NABERHUIS Full Name Sign:	1t. 7	VI.o. I.	Oct. 16, 2000
Full Name Sign	ature	1 avenus	Date of Signature
		•	Date of Signature
Inventor & Home Address Information: (If more than for	our inventors, include ad	dl. information on a copy of this form	1 & attach to this document)
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Inventor's Full Name			
Xia Sheng Street			
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Description of Invention: Please preserve all records of the invention and attach additional pages for the following. Each additional page should be signed and dated by the inventor(s) and witness(es).

A. Prior solutions and their disadvantages (if available, attach copies of product literature, technical articles, patents, etc.).

As dielectric layer is used to delineate the regions to be anodized in parous silicon emitters. An above The electric field is intermitied at the boundry of the dielectric mask. This causes the anodization process to accelerates along the boundary of the mask and causes non-uniform anodization

B. Problems solved by the invention.

the non uniform anodization is minimized when on metallic or conductive material, e.g., chrome, gold, platinum, is used as the anodization mask.

C. Advantages of the invention over what has been done before.

A more uniform anadization and improved electron

Description of the construction and operation of the invention (include appropriate schematic, block, & timing diagrams; drawings; samples; graphs; flowcharts; computer listings; test results; etc.)

To achieve anodization of porous silicon emitters, a metallic mask is used to delineate the intended region to be anodized. The field distribution is depicted in the attached diagram.

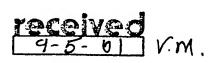
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COMPANY CONFIDENTIAL PAGE 54

Description of Invention: Please preserve all records of the invention and attach additional pages for the following. Each additional page should be signed and dated by the inventor(s) and witness(es).

Prior solutions and their disadvantages (if available, attach copies of product literature, technical articles, patents, etc.).

Electron sources from flat emission surfaces are used for various applications. A patterned dielectric layer is formed on top of the electron source to confine the electron emission to specific regions where no dielectric layer is present. The boundary lines of the dielectric layer, however, tend to have a higher electric field. This causes the electron source to emit preferentially along the border of the emission area and causes device failure

В. Problems solved by the invention.

The high field concentration along the border of the electron emission regions is eliminated.

Ċ. Advantages of the invention over what has been done before.

The elimination of the higher field improves the uniformity of the electron emission and improved the fife time and stability of electron emission.

Description of the construction and operation of the invention (include appropriate schematic, block, & timing diagrams; drawings; samples; D. graphs; flowcharts; computer listings; test results; etc.)

The fabrication process of the electron source is depicted in the following figures.

In prior art the following three steps are used to define the emission area.

Figure 1P. A thin layer of polycrystalline silicon is grown on top of single crystalline silicon.

Figure 2P. Prior Art. A layer of dielectric material, e.g. SiO2 or Si3N4, is grown or deposited.

Figure 3P. Prior art. The dielectric layer is patterned to define the emission area.

In the present invention, the following steps are used.

Figure 1I. A layer of dielectric material, e.g. SiO2 or Si3N4, Is grown or deposited.

Figure 21. The dielectric layer is patterned to define the emission area.

Figure 3I. A thin layer of polycrystalline silicon is grown on top of the single crystalline silicon and the dielectric.

In both the prior art and the present invention

Figure 4. Dielectric layer grown over the structure. When the thermal oxidation is used for this step, a high field along the boarder for the devices is produced with the prior art. The high field is eliminated with the present invention.

Fig 1P	Present Invention
Palus to the Manual to the same of the sam	Fig 1i
Poly crystalline silicon (Poly) single crystal silicon (c-si)	dielectric C-Si
Fig 2P	
dielectric Poly	Figai
C-S;	dielectric C-Si
Fig 3P	Figsi
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C- 3 <i>i</i>	dielectric